

## Certificate of Calibration

Standard Reference Materials

1504

1505

1506

For

## Permittivity

(7940 Fused Silica)

These Standard Reference Materials were cut from a mass of 7940 Fused Silica and are intended for the following uses:

No. 1504—A rough-cut blank for making a 2 inch disk for a low-frequency, capacity-type holder.

No. 1505—A rough-cut blank for a 0.4 inch by 0.9 inch rectangular x-band waveguide.

No. 1506—A rough-cut blank for a nominal one-inch diameter cylindrical waveguide.

The permittivity of these materials relative to vacuum (not air) is given in the following table.

Frequency Hz	Relative Permittivity	Loss Tangent × 10
103	$3.8350 \pm 0.30\%$	1.86 ± 0.84
104	$3.8317 \pm .30\%$	$1.14 \pm .79$
105	$3.8265 \pm .31\%$	$0.33 \pm .69$
106	$3.8255 \pm .31\%$	$0.34 \pm .74$
10*	$3.8258 \pm .37\%$	$0.20 \pm .86$
10°	$3.83 \pm .67\%$	1. $\pm 1.20$
1010	$3.8315 \pm .37\%$	$1.46 \pm 0.84$

Each value in the above table is an average of several measurements made by the National Bureau of tandards and at most frequencies also by the National Physical Laboratory of England and the National esearch Council of Canada. In forming the average, each laboratory's result has been weighted inversely s the uncertainty quoted by that laboratory. The uncertainty given in the table represents the uncertainties ormally quoted by the several laboratories, suitably combined and then increased to allow for possible thomogeneity of the material from which this specimen was cut. For additional information, see paper on International Comparison of Dielectric Measurements" by H. E. Bussey, J. E. Gray, E. C. Bamberger, Rushton, G. Russell, B. W. Petley, and D. Morris, IEEE Transactions on Instrumentation and Measurement, Volume IM-13, pp 305-311 (1964).